  



**National Facility for Atom Probe Tomography (NFAPT)**

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**Research Proposal**

Date:

1. Name of the project investigator and address:

Name of the student involved in this work and mobile number:

1. Number of samples:

Briefly describe fabrication method and nature of sample: *(max. 50 words) (Metals, semiconductors, ceramics, composites, nanowires, etc.)*

1. Nature of sample:

|  |  |
| --- | --- |
| * Is it magnetic? Yes/No | * Is it electron beam sensitive? Yes/No |
| * Is it volatile? Yes/No | * Is it flammable? Yes/No |

1. Motivation for using atom probe tomography, in comparison to other characterization tools:

*(max. 100 words)*

1. Nature of work: *(max. 50 words)*

*(Grain boundary/phase boundary/interface analysis, cluster analysis, dopant mapping, etc.)*

1. Is the atom probe sample already prepared?
   * *If Yes, please describe the details of preparation method and sample dimensions (max. 50 words)*
   * *If No, the type of sample preparation needed. (Electropolishing or Focused Ion Beam)*
2. Is site specific sample preparation mandatory? If so, mention the specific area in the sample.

**Note:**

* + Please share results that may be helpful for APT sample preparation and APT analysis (ex: *SEM and TEM micrographs*)
  + Please list one or two APT publications related to this work, if available
  + Samples sent to IITM should be in well-polished condition, e.g., suitable for EBSD.

**Office use:**

Proposal No.: Received date: